

**Search Notes**

Application/Control No.

10/689,091

Examiner

Leon J. Harper

Applicant(s)/Patent under  
Reexamination

CHANG, YUAN-CHI

Art Unit

2166

**SEARCHED**

Class	Subclass	Date	Examiner
707	10,13,104, 1,100,101	5/31/2006	LJH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR